

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**High-voltage switchgear and controlgear –
Part 101: Synthetic testing**

**Appareillage à haute tension –
Partie 101: Essais synthétiques**

Withdrawn



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HIGH-VOLTAGE SWITCHGEAR AND CONTROLGEAR –**Part 101: Synthetic testing**

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This second edition cancels and replaces the first edition published in 2006 and its Amendment 1 published in 2010. It constitutes a technical revision.

This edition includes the following significant technical changes with respect to the first edition:

- addition of the new rated voltages of 1 100 kV and 1 200 kV;
- revision of Annex F regarding circuit-breakers with opening resistors;
- alignment with the second edition of IEC 62271-100:2008 and its Amendment 1 (2012).

The text of this standard is based on the first edition of IEC 62271-101 and the following documents:

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This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This publication shall be read in conjunction with IEC 62271-100, published in 2008, to which it refers. The numbering of the subclauses of Clause 6 is the same as in IEC 62271-100. However, not all subclauses of IEC 62271-100 are addressed; merely those where synthetic testing has introduced changes.

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